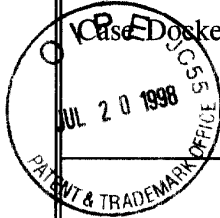


07-23-1998

U.S. :

ICE

MRD 7-20-98



Case Docket No. 980182

100771671

DEPARTMENT OF COMMERCE
Patent and Trademark Office

RECORDATION FORM COVER SHEET
PATENTS ONLY

To the Assistant Commissioner for Patents.
Please record the attached original documents or copy thereof.

1. Name of conveying party(ies):

Masataka MIZUKOSHI, Hidehiko AKASAKI, Masao NAKANO, Yasuhiro FUJII,
Shinnosuke KAMATA, Makoto YANAGISAWA and Yasurou MATSUZAKI

Additional name(s) of conveying party(ies) attached? NO

2. Name and address of receiving party(ies):

Name: FUJITSU LIMITED

Street Address:

1-1, Kamikodanaka 4-chome, Nakahara-ku,
Kawasaki-shi, Kanagawa 211-8588, Japan

Additional name(s) & address(es) attached? NO

3. Nature of conveyance: **Assignment**

Execution Date: **June 9, 1998**

4. Title:

SEMICONDUCTOR WAFER TESTING METHOD WITH
IMPROVED PROBE PIN CONTACT

5. Application number(s) or patent number(s): 09/030,349

If this document is being filed together with a new application, the execution date of
the application is:

07/22/1998 DMLJYEN 00000095 09030349

01 FC:581

40.00 00

Additional numbers attached? NO

6. Name and address of party to whom correspondence concerning document should be mailed:

Name: Armstrong, Westerman, Hattori,
McLeland & Naughton
Suite 1000
1725 K Street, N.W.
Washington, D.C. 20006

7. Total number of applications and patents involved: 1

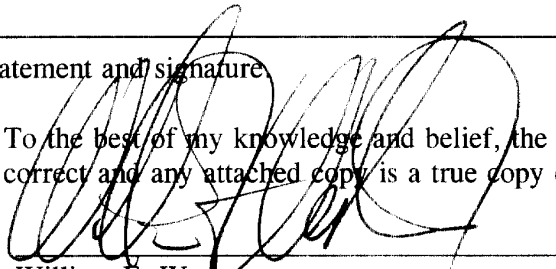
8. Total fee (37 CFR 3.41). \$ **40.00**

XX Check enclosed

9. Deposit Account No.: **01-2340**

10. Statement and signature

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.



William F. Westerman
Reg. No.: 29,988

Date July 20, 1998

Total number of pages including cover sheet: 4

WFW/tmb

Armstrong, Westerman, Hattori, McLeland & Naughton

Docket No. _____

U.S. ASSIGNMENT

IN CONSIDERATION of the sum of One Dollar (\$1.00), and of other good and valuable consideration paid to the undersigned inventor(s) (hereinafter ASSIGNOR) by

(Insert ASSIGNEE's
Name(s) Address(es))

FUJITSU LIMITED, 1-1, Kamikodanaka 4-chome, Nakahara-ku,
Kawasaki-shi, Kanagawa, 211-8588 Japan

(hereinafter ASSIGNEE), the receipt of which is hereby acknowledged, the undersigned ASSIGNOR hereby sells, assigns and transfers to ASSIGNEE the entire and exclusive right, title and interest to the invention entitled

(Title of Invention)

SEMICONDUCTOR WAFER TESTING METHOD WITH IMPROVED PROBE PIN CONTACT

(*If the assignment is
being filed after the filing
of the application, this
section must be
completed)

for which application for Letters Patent of the United States was executed on even date herewith unless otherwise indicated below:

*filed on February 25, 1998, Serial No. 09/030,349
(Armstrong, Westerman, Hattori, McLeland & Naughton is hereby authorized to insert the series code, serial number and/or filing date hereon, when known)

and all Letters Patent of the United States to be obtained therefor on said application or any continuation, divisional, substitute, reissue or reexamination thereof for the full term or terms for which the same may be granted.

The ASSIGNOR agrees to execute all papers necessary in connection with the application and any continuation, divisional, reissue or reexamination applications thereof and also to execute separate assignments in connection with such applications as the ASSIGNEE may deem necessary or expedient.

The ASSIGNOR agrees to execute all papers necessary in connection with any interference, litigation, or other legal proceeding which may be declared concerning this application or any continuation, divisional, reissue or reexamination thereof or Letters Patent or reissue patent issued thereon and to cooperate with the ASSIGNEE in every way possible in obtaining and producing evidence and proceeding with such interference, litigation, or other legal proceeding.

IN WITNESS WHEREOF, the undersigned inventor(s) has (have) affixed his/her/their signature(s).

(Signatures)

<u>Masataka Mizukoshi</u> (SIGNATURE)	Masataka Mizukoshi (TYPE NAME)	June 9, 1998 (DATE)
<u>Hidehiko Akasaki</u> (SIGNATURE)	Hidehiko Akasaki (TYPE NAME)	June 9, 1998 (DATE)
<u>Masao Nakano</u> (SIGNATURE)	Masao Nakano (TYPE NAME)	June 9, 1998 (DATE)
<u>Yasuhiro Fujii</u> (SIGNATURE)	Yasuhiro Fujii (TYPE NAME)	June 9, 1998 (DATE)
<u>Shinnosuke Kamata</u> (SIGNATURE)	Shinnosuke Kamata (TYPE NAME)	June 9, 1998 (DATE)
<u>Makoto Yanagisawa</u> (SIGNATURE)	Makoto Yanagisawa (TYPE NAME)	June 9, 1998 (DATE)
<u>Yasurou Matsuzaki</u> (SIGNATURE)	Yasurou Matsuzaki (TYPE NAME)	June 9, 1998 (DATE)

NO LEGALIZATION REQUIRED

PATENT
REEL: 9319 FRAME: 0735

<u>Toyonobu Yamada</u>	Toyonobu Yamada	June 9, 1998
(SIGNATURE)	(TYPE NAME)	(DATE)
<u>Masami Matsuoka</u>	Masami Matsuoka	June 9, 1998
(SIGNATURE)	(TYPE NAME)	(DATE)
<u>Hiroyoshi Tomita</u>	Hiroyoshi Tomita	June 9, 1998
(SIGNATURE)	(TYPE NAME)	(DATE)
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